

Automated assembly of large double-sided microstrip detectors for the CBM Silicon Tracking System at FAIR

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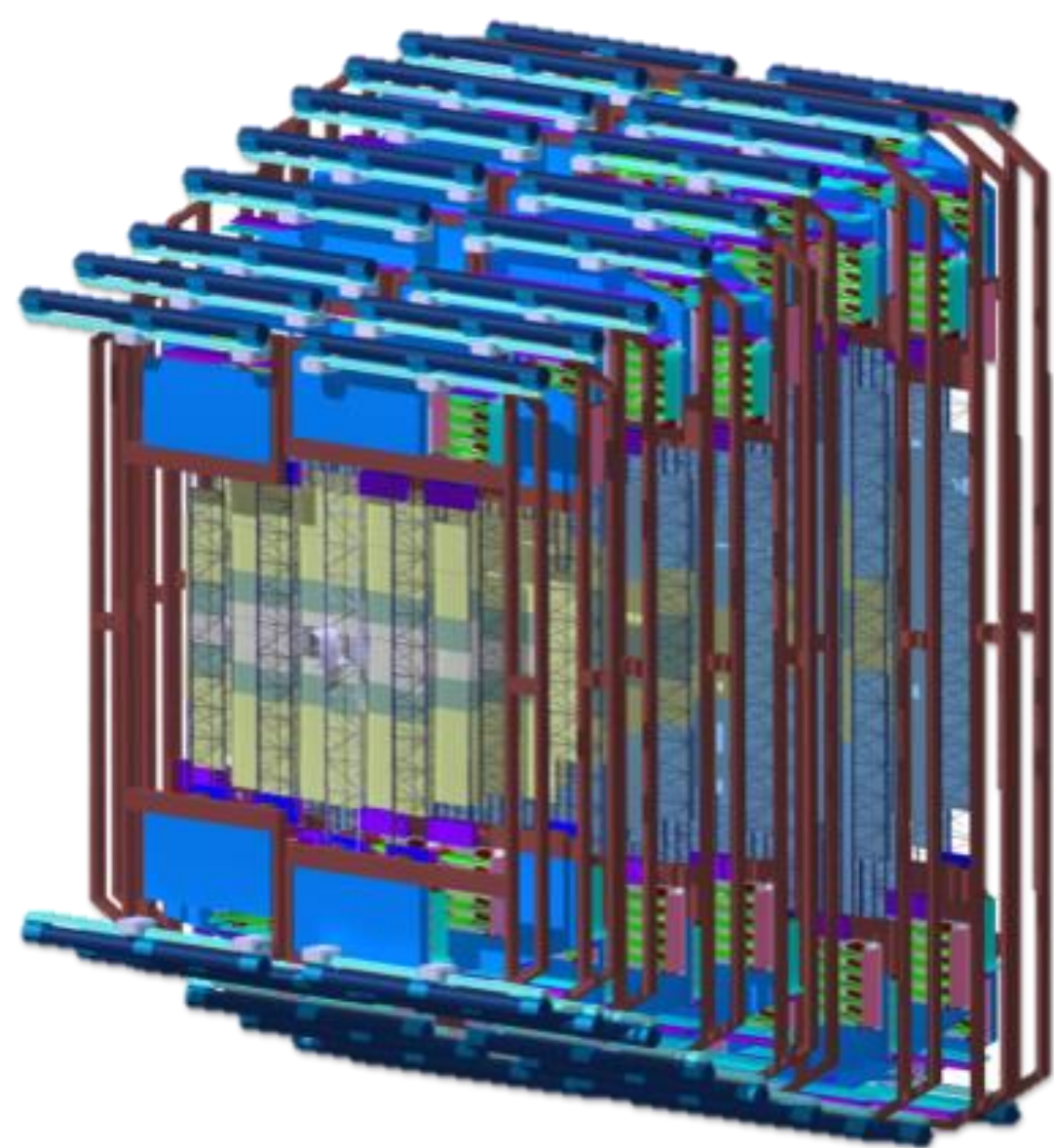


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- CBM will be one of the major scientific pillars of the future FAIR facility
- Investigation of QCD phase diagram at highest baryon densities

Silicon Tracking System (STS)

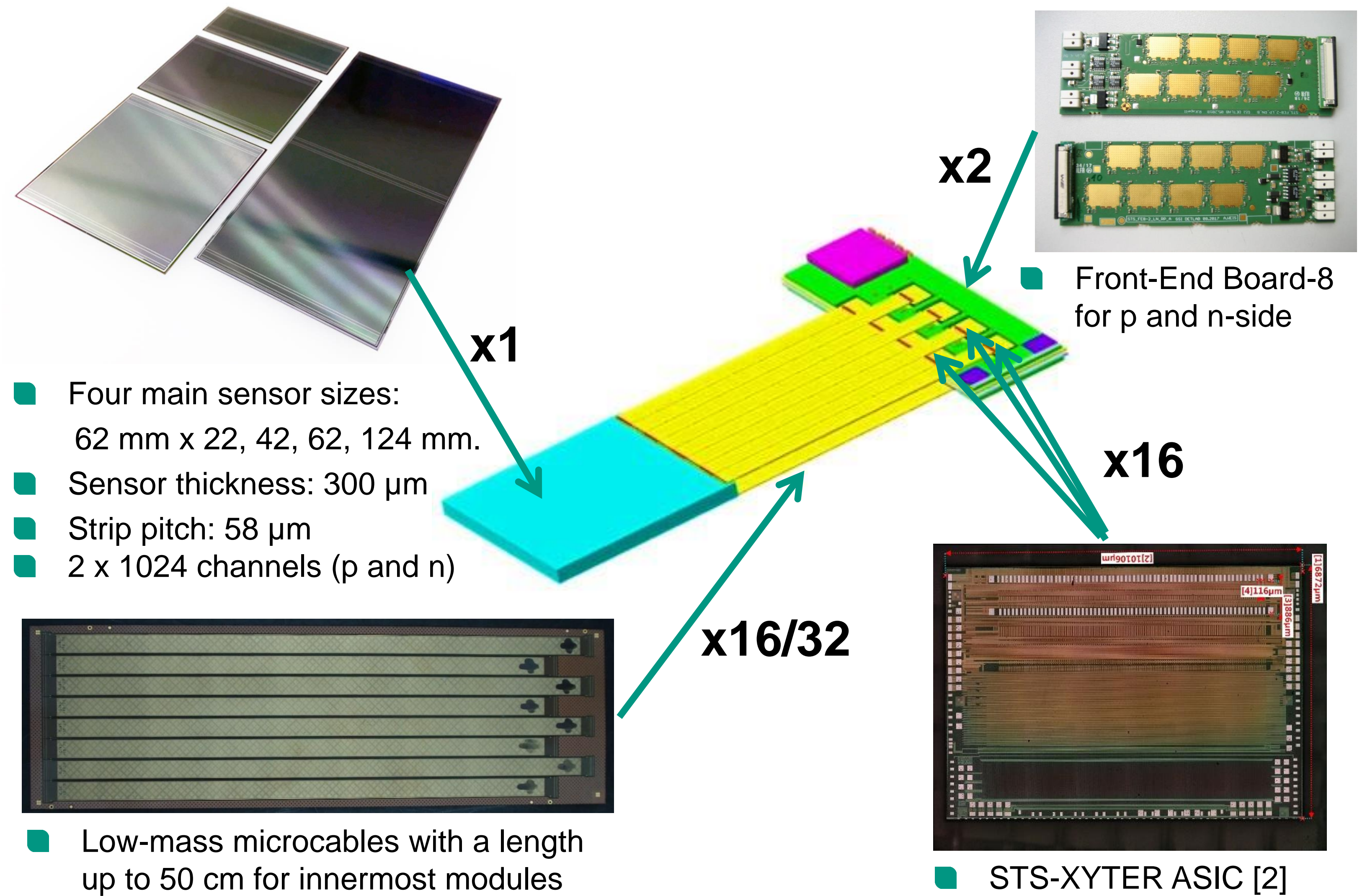
- One of the core detectors of CBM located inside the dipole magnet [1]
- Track reconstruction and momentum determination of charged particles
- Track mult. ≤ 700 per central Au+Au collision in aperture $2.5^\circ < \theta < 25^\circ$
- Momentum resolution $\Delta p/p < 2\%$
- Lifetime fluence up to $1 \times 10^{14} n_{eq}$ in innermost region



STS conception

- Eight tracking stations 0.3 m to 1 m downstream of the target
- 896 detector modules arranged in 106 ladders of 23 variations
- Readout electronics located in the periphery
- Module structure is rather complex

STS detector module

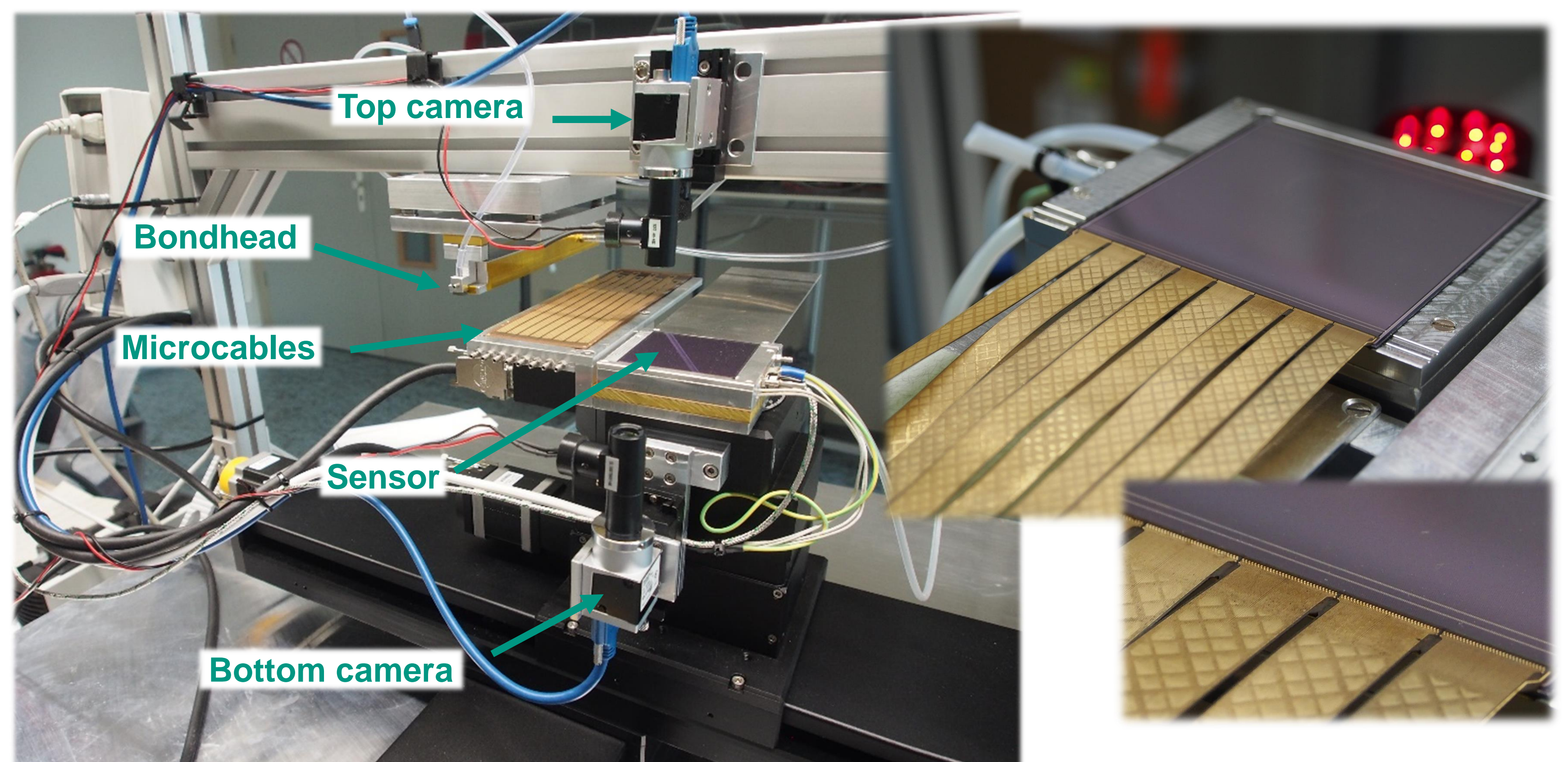


Automated bonder machine developed at KIT

- Complementing the established Al TAB bonding interconnection technology based on an aluminum microcable, a novel high-density interconnection technology based on a gold stud – solder paste flip chip process and a copper microcable has been developed at KIT [3]. To fully exploit its automation capabilities, an in-house bonder machine has been developed in parallel.

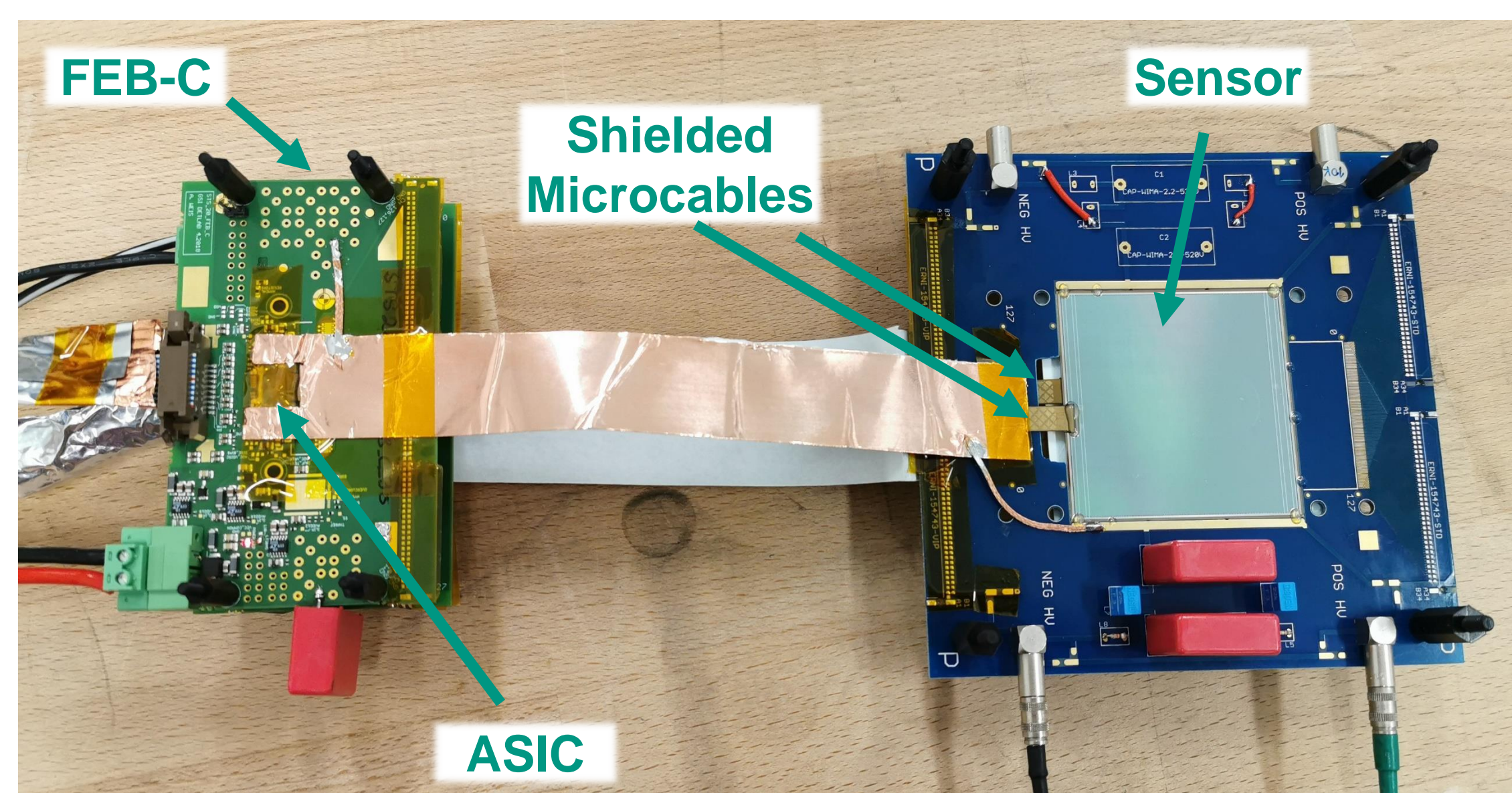
Cable bonder characteristics

- Four stepper motors in x, y, z, phi with sub-micron step resolution to achieve alignment accuracy $\leq 8 \mu\text{m}$
- Dual-camera system including calibration mechanism for precise alignment of microcable and sensor
- Specialized mechanics for the handling of STS module components
- Valve island for automated pneumatic control
- Heatable bondhead and sensor plate with automated temperature control
- Pressurized air cooling



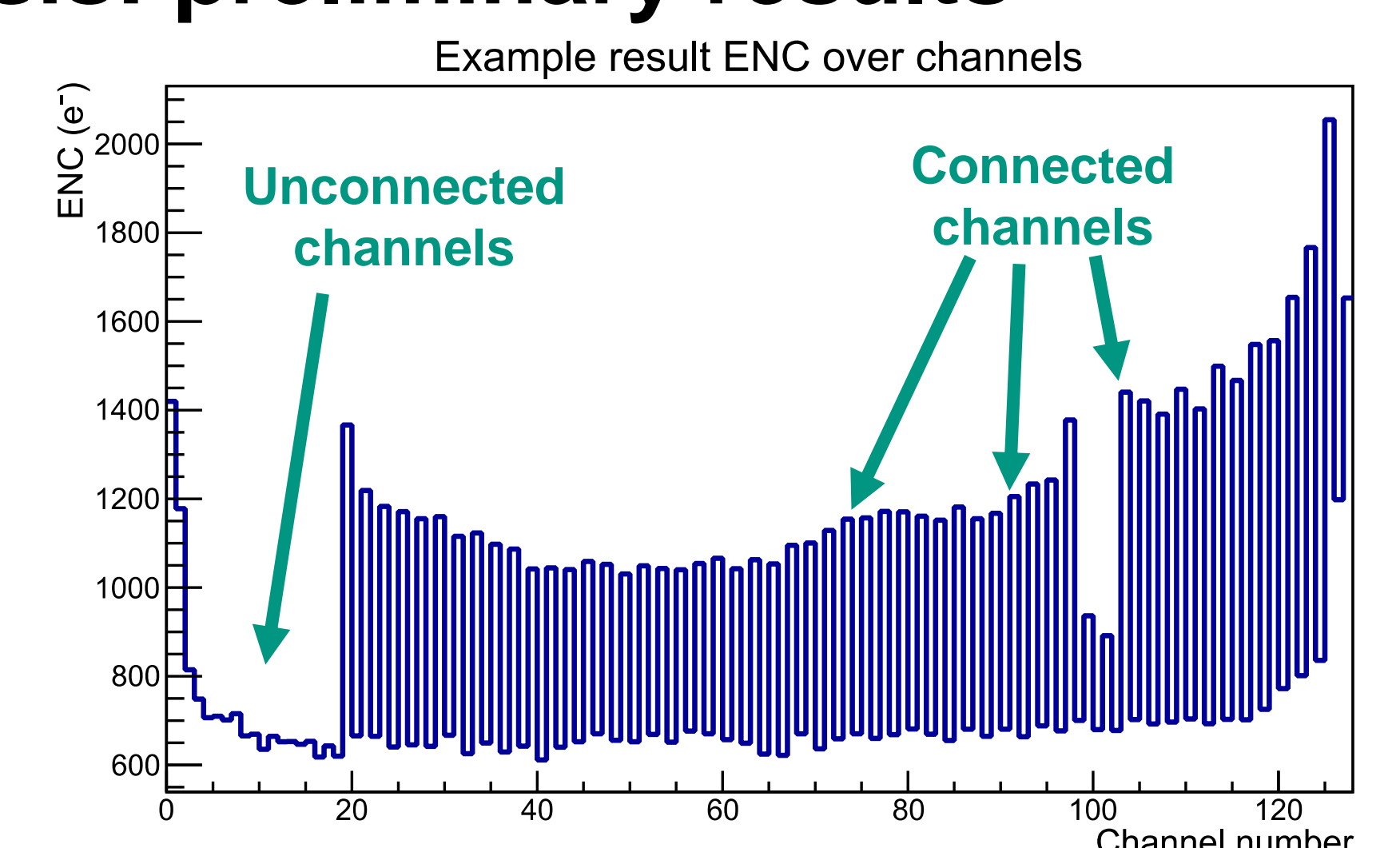
Test setup

- 6.2 x 6.2 cm^2 double-sided sensor biased at $\pm 150 \text{ V}$
- One copper microcable for n-side and p-side
- Two Front-End Boards type C (FEB-C), each hosting one STX-XYTER readout ASIC
- Readout via AFCK board hosting Kintex7 FPGA controlled by IPbus
- Full noise analysis performed inside aluminum shielding box with the help of STX-XYTERs internal test pulsing capability



Noise analysis: preliminary results

- ENC analysis is essential for the QA of detector modules during R&D as well as production
 - Identification of possible bad connections on sensor or ASIC side
 - Comparison between interconnection technologies
 - Influence of different cable and sensor sizes
 - Optimization of shielding and grounding



- Expected ENC
$$460 e^- (\text{ASIC}) + \left(0.44 \frac{\text{pF}}{\text{cm}} * 20 \text{ cm} (\text{cable}) + 1.52 \frac{\text{pF}}{\text{cm}} * 6.02 \text{ cm} (\text{sensor}) \right) * 27.4 \frac{e^-}{\text{pF}} = 952 e^-$$
- Measured ENC for connected channels
 - P-side: $1000 \pm 80 e^-$
 - N-side: $1100 \pm 80 e^-$
- Preliminary results are comparable to aluminum TAB bonding technology.

References:

- [1] The CBM collaboration, *Technical Design Report for the CBM STS*, Darmstadt, 2013
- [2] K. Kasinski et al., *Characterization of the STS/MUCH-XYTER2, a 128-channel time and amplitude measurement IC for gas and silicon microstrip sensors*, NIM A, Vol. 30 Issue 9 (2018)
- [3] P. Pfistner et al., *Novel production method for large double-sided microstrip detectors of the CBM Silicon Tracking System at FAIR*, PoS(TWEPP2018)144 (2018)